

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	523	(test\$3 near3 (IC or (integrated adj2 circuit))) same (scan adj2 (chain\$1 or register\$1 or unit\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:39
L2	218	(test\$3 near3 (IC or (integrated adj2 circuit))) same (scan adj2 (chains or registers or units))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:39
L3	14	(test\$3 near3 (IC or (integrated adj2 circuit))) same ((scan adj2 (chains or registers or units)) near10 (parallel or in-parallel))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:49
L10	8	(scan adj2 (chains or registers or units)) and out-of-phase	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:55
L11	10	parker-kenneth.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:46
L13	147	(test\$3 near3 (IC or (integrated adj2 circuit))) and ((scan adj2 (chains or registers or units)) and (parallel or in-parallel)) and phase	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:49
L14	14	(test\$3 near3 (IC or (integrated adj2 circuit))) same ((scan adj2 (chains or registers or units)) near10 (parallel or in-parallel))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:49
L15	1	(test\$3 near3 (IC or (integrated adj2 circuit))) same ((scan adj2 (chains or registers or units)) same (parallel or in-parallel)) same phase	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:50
L16	1	((scan adj2 (chains or registers or units)) same (parallel or in-parallel))) and out-of-phase	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:50
L17	1	(test\$3 near3 (IC or (integrated adj2 circuit))) same ((scan adj2 (chains or registers or units)) same (parallel or in-parallel)) same phase	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:50
L18	1	(scan adj2 (chains or registers or units)) same out-of-phase	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:55

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L19	1	((scan adj2 (chains or registers or units)) near10 parallel) and out-of-phase	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 14:56
L20	1	((scan adj2 (chains or registers or units)) same parallel) and out-of-phase	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 15:12
L24	120	(scan adj2 chain) near3 parallel	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 15:14
L25	2	((scan adj2 chain) near3 parallel) and out-of-phase	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/02/28 15:14


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» Key

IEEE JNL IEEE Journal or Magazine

IEEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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 Volume 19, Issue 10, Oct. 2000 Page(s):1175 - 1188
 Digital Object Identifier 10.1109/43.875312
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- ☐ 2. **Automated synthesis of large phase shifters for built-in self-test**
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- ☐ 3. **Modular logic built-in self-test for IP cores**
 Rajski, J.; Tyszer, J.;
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- ☐ 4. **Design of phase shifters for BIST applications**
 Rajski, J.; Tyszer, J.;
[VLSI Test Symposium, 1998. Proceedings. 16th IEEE](#)
 26-30 April 1998 Page(s):218 - 224
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